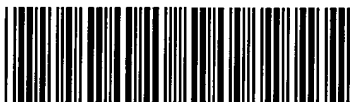


Search Notes

Application/Control No.

10/630,977

Examiner

TAN X. DINH

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see search history printout)	1/30/2007	T.D